

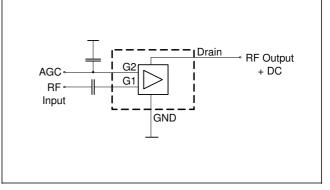
BG3230_BG3230R

DUAL N-Channel MOSFET Tetrode

- Low noise gain controlled input stages of UHFand VHF-tuners with 5V supply voltage
- Two AGC amplifiers in one single package
- Integrated stabilized bias network
- Integrated gate protection diodes
- High gain, low noise figure
- Improved cross modulation at gain reduction
- High AGC-range







ESD (Electrostatic discharge) sensitive device, observe handling precaution!

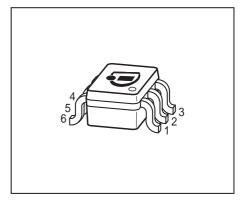
Туре	Package	Pin Configuration						Marking
BG3230	SOT363	1=G1*	2=G2	3=D*	4=D**	5=S	6=G1**	KBs
BG3230R	SOT363	1=G1*	2=S	3=D*	4=D**	5=G2	6=G1**	Kls

* For amp. A; ** for amp. B

180° rotated tape loading orientation available

Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V _{DS}	8	V
Continuous drain current	I _D	25	mA
Gate 1/ gate 2-source current	± <i>I</i> _{G1/2SM}	1	
Gate 1/ gate 2-source voltage	$\pm V_{G1/G2S}$	6	V
Total power dissipation	P _{tot}	200	mW
Storage temperature	T _{stg}	-55 150	°C
Channel temperature	T _{ch}	150	





Thermal Resistance

Parameter	Symbol	Value	Unit
Channel - soldering point ¹⁾	R _{thchs}	≤ 280	K/W

Electrical Characteristics

Parameter	Symbol	Values			Unit	
			typ.	max.]	
DC Characteristics			-		•	
Drain-source breakdown voltage	V _{(BR)DS}	12	-	-	V	
$I_{\rm D} = 100 \ \mu {\rm A}, \ V_{\rm G1S} = 0 \ , \ V_{\rm G2S} = 0$						
Gate1-source breakdown voltage	+V _{(BR)G1SS}	6	-	15		
$+I_{G1S} = 10 \text{ mA}, V_{G2S} = 0, V_{DS} = 0$						
Gate2 source breakdown voltage	±V _{(BR)G2SS}	6	-	15		
$\pm I_{G2S} = 10 \text{ mA}, V_{G1S} = 0, V_{DS} = 0$						
Gate1-source leakage current	+I _{G1SS}	-	-	50	μA	
$V_{G1S} = 6 V, V_{G2S} = 0$						
Gate 2 source leakage current	±I _{G2SS}	-	-	50	nA	
$\pm V_{G2S} = 6 V, V_{G1S} = 0, V_{DS} = 0$						
Drain current	I _{DSS}	-	-	100	μΑ	
$V_{\text{DS}} = 5 \text{ V}, \ V_{\text{G1S}} = 0 \ , \ V_{\text{G2S}} = 4 \text{ V}$						
Operating current (selfbiased)	I _{DSO}	-	13	-	mA	
$V_{\text{DS}} = 5 \text{ V}, \ V_{\text{G2S}} = 4 \text{ V}$						
Gate2-source pinch-off voltage	V _{G2S(p)}	-	1	-	V	
$V_{\rm DS} = 5 \text{ V}, I_{\rm D} = 100 \ \mu\text{A}$						

¹For calculation of $R_{\rm thJA}$ please refer to Application Note Thermal Resistance



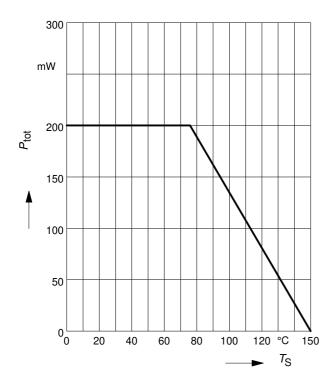
Electrical Characteristics

Parameter	Symbol	Values			Unit
		min.	typ.	max.	1
AC Characteristics - (verified by random sampli	ng)				
Forward transconductance	g _{fs}	-	33	-	mS
$V_{\rm DS} = 5 \rm V, V_{\rm G2S} = 4 \rm V$					
Gate1 input capacitance	C _{g1ss}	-	1.9	-	pF
$V_{\rm DS} = 5 \text{ V}, V_{\rm G2S} = 4 \text{ V}, f = 10 \text{ MHz}$					
Output capacitance	C _{dss}	-	1.1	-	
$V_{\rm DS} = 5 \text{ V}, V_{\rm G2S} = 4 \text{ V}, f = 10 \text{ MHz}$					
Power gain (self biased)	Gp				dB
$V_{\text{DS}} = 5 \text{ V}, V_{\text{G2S}} = 4 \text{ V}, f = 800 \text{ MHz}$		-	24	-	
$V_{\rm DS} = 5 \text{ V}, V_{\rm G2S} = 4 \text{ V}, f = 45 \text{ MHz}$		-	31	-	
Noise figure (self biased)	F				dB
$V_{\text{DS}} = 5 \text{ V}, V_{\text{G2S}} = 4 \text{ V}, f = 800 \text{ MHz}$		-	1.3	-	
$V_{\text{DS}} = 5 \text{ V}, V_{\text{G2S}} = 4 \text{ V}, f = 45 \text{ MHz}$		-	1.7	-	
Gain control range	ΔG_{p}	45	-	-	
$V_{\text{DS}} = 5 \text{ V}, V_{\text{G2S}} = 40 \text{ V}, f = 800 \text{ MHz}$					
Cross-modulation $k=1\%$, $f_w=50MHz$, $f_{unw}=60MHz$	Z X _{mod}				-
AGC = 0 dB		90	-	-	
<i>AGC</i> = 10 dB		-	87	-	
AGC = 40 dB		96	100	-	

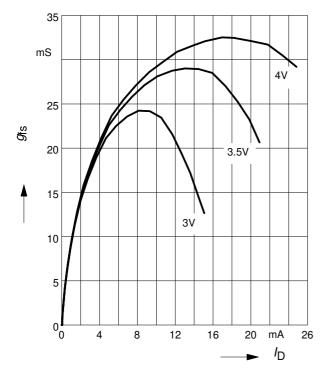


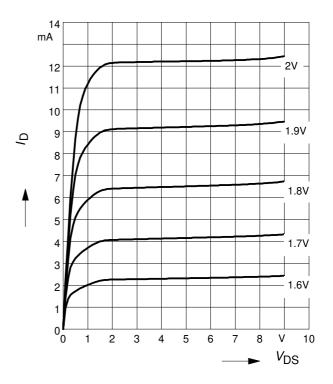
Total power dissipation $P_{tot} = f(T_S)$

Output characteristics $I_{D} = f(V_{DS})$

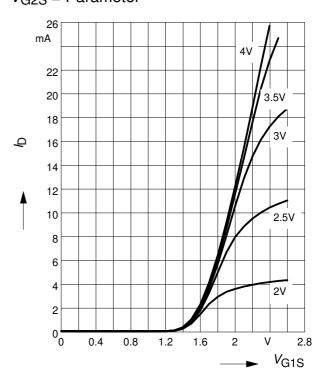


Gate 1 forward transconductance $g_{fs} = f(I_D)$ $V_{DS} = 5V, V_{G2S} = Parameter$





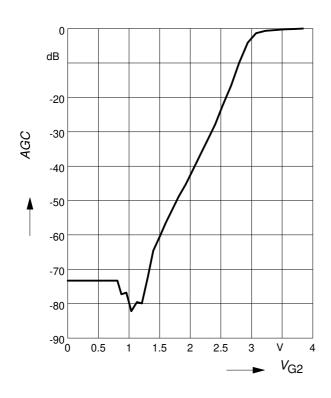
Drain current $I_D = f(V_{G1S})$ $V_{DS} = 5V$ $V_{G2S} = Parameter$





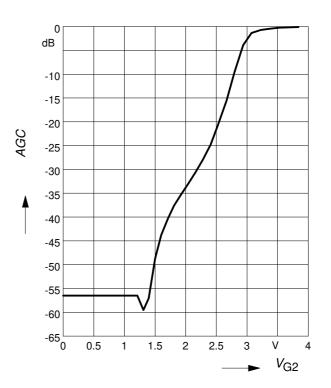
AGC characteristic $AGC = f(V_{G2S})$

f = 200 MHz

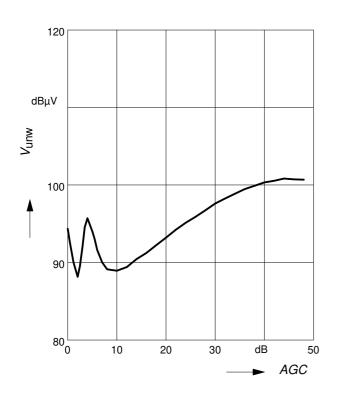


AGC characteristic $AGC = f(V_{G2S})$

f = 800 MHz

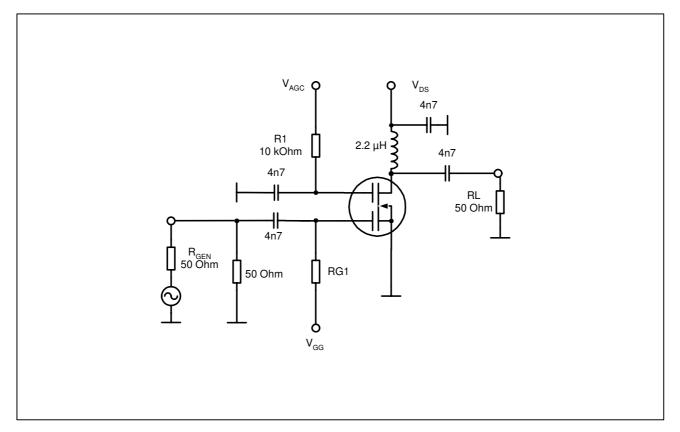


 $\label{eq:crossmodulation} \begin{array}{l} \textit{Crossmodulation} \ \textit{V}_{unw} = (\textit{AGC}) \\ \textit{V}_{DS} = 5 \ \textit{V}, \ \textit{R}_{g1} = 68 \ \textit{k}\Omega \end{array}$

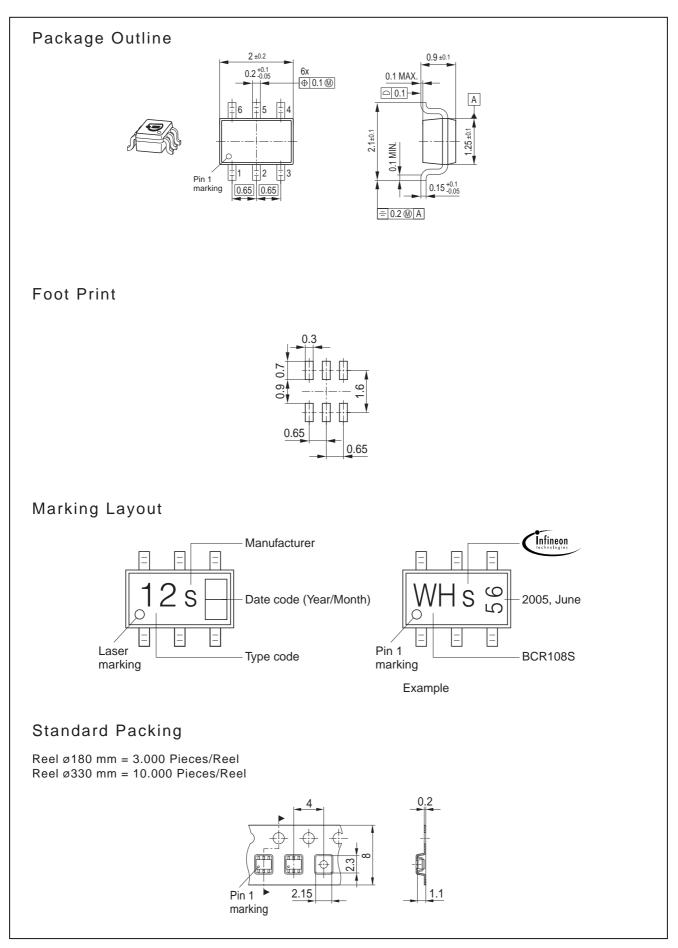




Crossmodulation test circuit









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